

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:)	Confirmation No.: 5721
Hidekazu MIYAIRI et al.)	Examiner: Jeffrey R. West
Serial No. 10/808,499)	Group Art Unit: 2857
Filed: March 25, 2004)	
For: METHOD FOR TESTING)	
SEMICONDUCTOR FILM,)	
SEMICONDUCTOR DEVICE AND)	
MANUFACTURING METHOD)	
THEREOF)	

AMENDMENT

Honorable Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to the Official Action dated July 22, 2010, please consider the following amendments and remarks in connection with the above-identified application.

Amendments to the Claims are reflected in the listing of claims, which begins on page 2 of this paper.

Remarks begin on page 12 of this paper.